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FDS7296N3

30V N-Channel PowerTrench® MOSFET

General Description

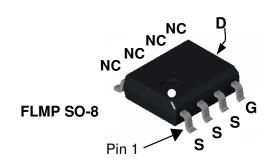
This N-Channel MOSFET in the thermally enhanced SO8 FLMP package has been designed specifically to improve the overall efficiency of DC/DC converters. Providing a balance of low RDS(ON) and Qg it is ideal for synchronous rectifier applications in both isolated and non-isolated topologies. It is also well suited for high and low side switch applications in Point of Load converters.

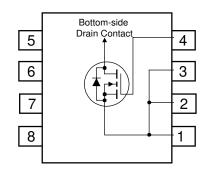
Applications

- · Secondary side Synchronous rectifier
- Synchronous Buck VRM and POL Converters

Features

- 15 A, 30 V $R_{DS(ON)} = 8 \text{ m}\Omega @ V_{GS} = 10 \text{ V}$ $R_{DS(ON)} = 11 \text{ m}\Omega @ V_{GS} = 4.5 \text{ V}$
- High performance trench technology for extremely low R_{DS(ON)}
- Optimized for low Qgd to enable fast switching and reduced CdV/dt gate coupling.
- SO-8 FLMP for enhanced thermal performance in an industry-standard package outline.





Absolute Maximum Ratings T_{A=25°C} unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		30	V
V _{GSS}	Gate-Source Voltage		±20	V
I _D	Drain Current - Continuous	(Note 1a)	15	А
	- Pulsed		60	
P _D	Power Dissipation for Single Operation	(Note 1a)	3.0	W
		(Note 1b)	1.5	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	0.5	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDS7296N3	FDS7296N3	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-Sc	ource Avalanche Ratings			l		I.
W _{DSS}	Drain-Source Avalanche Energy	Single Pulse, $V_{DD} = 27 \text{ V}$, $I_D=15 \text{ A}$			189	mJ
I _{AR}	Drain-Source Avalanche Current				15	Α
Off Char	acteristics			,	•	
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = 250 \mu\text{A}$	30			V
<u>ΔBV_{DSS}</u> ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, Referenced to 25°C		28		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			1	μΑ
I_{GSS}	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			± 100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1	1.8	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		-0.5		mV/°C
$R_{\text{DS(on)}}$	Static Drain–Source On–Resistance	$V_{GS} = 10 \text{ V}, \qquad I_D = 15 \text{ A} $ $V_{GS} = 4.5 \text{ V}, \qquad I_D = 13 \text{ A} $ $V_{GS} = 10 \text{ V}, \qquad I_D = 15 \text{ A}, T_J = 125^{\circ}\text{C}$		6.5 8.2 9.7	8 11 13	mΩ
g FS	Forward Transconductance	$V_{DS} = 10 \text{ V}, \qquad I_{D} = 15 \text{ A}$		58		S
Dynamic	Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = 15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		1540		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		430		pF
C _{rss}	Reverse Transfer Capacitance			140		pF
R_{G}	Gate Resistance	$V_{GS} = 15 \text{ mV}, f = 1.0 \text{ MHz}$		1.0		Ω
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 15 \text{ V}, \qquad I_D = 1 \text{ A},$		10	20	ns
t _r	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		4	9	ns
t _{d(off)}	Turn-Off Delay Time			27	44	ns
t _f	Turn-Off Fall Time			14	25	ns
Qg	Total Gate Charge	$V_{DS} = 15 \text{ V}, I_{D} = 15 \text{ A}, V_{GS} = 5 \text{ V}$		12.7	18	nC
Qg	Total Gate Charge	$V_{DS} = 15 \text{ V}, I_{D} = 15 \text{ A}, V_{GS} = 10 \text{ V}$		23	32	nC
Q_{gs}	Gate-Source Charge			4.2		nC
Q_{gd}	Gate-Drain Charge			3.5		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Source				2.5	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 2.5 \text{ A}$ (Note 2)		0.7	1.2	V
t _{rr}	Diode Reverse Recovery Time	I _F = 15 A,		27		nS
Qrr	Diode Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A}/\mu\text{s}$		19		nC

Notes

 R_{BJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{BJC} is guaranteed by design while R_{BCA} is determined by the user's board design.



a) 40°C/W when mounted on a 1in² pad of 2 oz copper



b) 85°C/W when mounted on a minimum pad of 2 oz copper

Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width < 300 μ s, Duty Cycle < 2.0%

Typical Characteristics

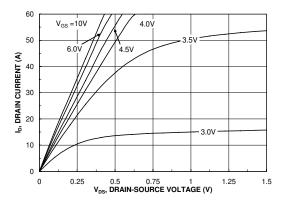


Figure 1. On-Region Characteristics.

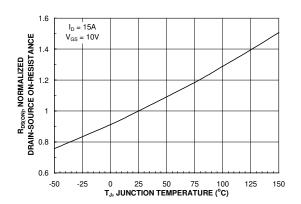


Figure 3. On-Resistance Variation withTemperature.

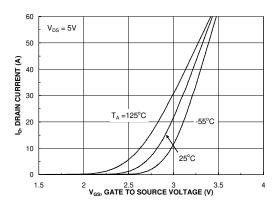


Figure 5. Transfer Characteristics.

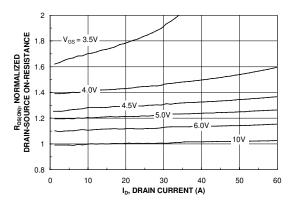


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

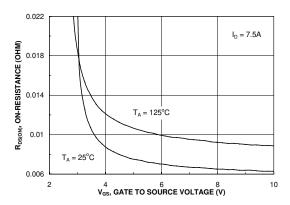


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

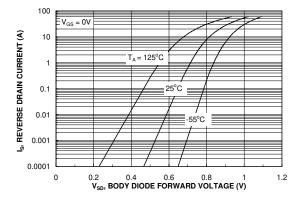
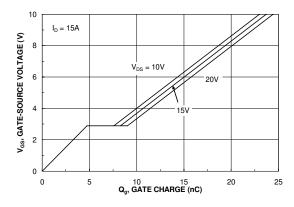


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



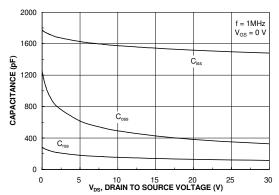
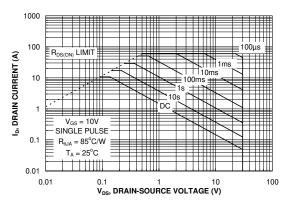


Figure 7. Gate Charge Characteristics.





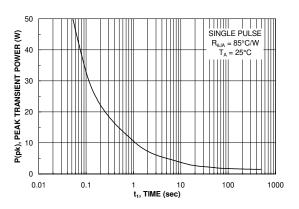


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

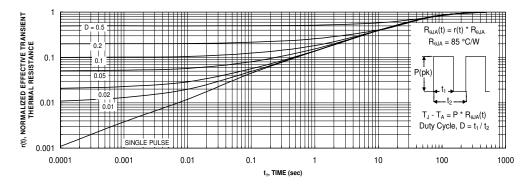


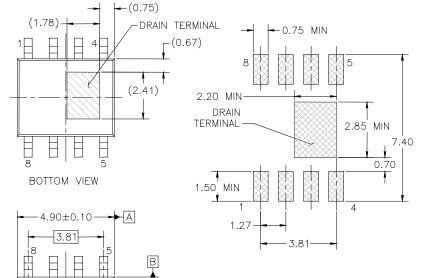
Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

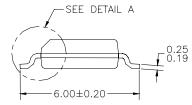
Dimensional Outline and Pad Layout

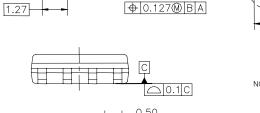
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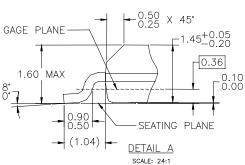


LAND PATTERN RECOMMENDATION





3.90±0.10



NOTES: UNLESS OTHERWISE SPECIFIED

- ALL DIMENSIONS ARE IN MILLIMETERS. STANDARD LEAD FINISH:
 20-80 MICROINCHES NICKEL/
 6 MICROINCHES MAX. PALLADIUM AND GOLD FLASH.
 NO JEDEC REGISTERED REFERENCE AS OF MARCH 2, 2000.

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	CoolFET™	FRFET™	MicroFET™	PowerTrench®	SuperSOT™-6
	$CROSSVOLT^{\text{TM}}$	GlobalOptoisolator™	MicroPak™	QFET®	SuperSOT™-8
	DOME™	GTO™ '	MICROWIRE™	QSTM	SyncFET™
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	EnSigna™	i-Lo TM	OCX^{TM}	RapidConfigure™	TruTranslation™
	FACT™	ImpliedDisconnect™	OCXPro [™]	RapidConnect™	UHC™
FACT Quiet Series™		OPTOLOGIC®	∞SerDes™	UltraFET®	
ACIOSS THE BOATG. ATOUTIG THE WORLS. ""		OPTOPLANAR™ PACMAN™ POP™	SILENT SWITCHER® SMART START™ SPM™	VCX™	

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